

**Notice of References Cited**

 Application/Control No.  
 09/847,309

 Applicant(s)/Patent Under  
 Reexamination  
 HARTMAN ET AL.

 Examiner  
 Todd Ingberg

 Art Unit  
 2124

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	V	"Test Environment Toolkit" Release Notes for TETware Release 3.3, TET3-RN-3.3, The Open Group Released September 18, 1998, pages 1 - 8
	W	"Test Environment Toolkit" TETware Programmer's Guide Revision 1.2 TET3-PG-1.2, The Open Group Released September 18, 1998, pages 1 - 258
	X	"Automated Test Generation from a Behavioral Model", James M. Clarke, Lucent Technologies, May 1998

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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